

Search Notes

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Jung Park

Applicant(s)/Patent under
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STEPHENS, ADRIAN P.

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SEARCHED

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INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
370/338, 328, 229, 230, 230.1, 235 (text search only - see history printout)	3/15/2007	JP
Text search in EAST (USPT, PGPUB) - see history printout	3/15/2007	JP
Internet search for IEEE standard	3/16/2007	JP